# TR636E-10164

## QUALITY EVALUATION TEST REPORT IT3-25H

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### [1] Objective:

To assess the performance and quality of the connectors, IT3-25H.

### [2] Specimens:

IT3-300P-25H (03)

IT3M-300S-BGA (57)

IT3D-300S-BGA (57)

[Above test specimens were tested in the condition as it is received from the client.]

### [3] Test period:

From: 2009-10-09 To: 2009-12-02

### [4] Test temperature:

18 °C to 28 °C

### [5] Test humidity:

25 %RH to 75 %RH

### [6] Test item, Number of specimens, Page No.

Test	Test item/		G	rou	p		Number of	Page
item No.	(Applicable standard)	Α	В	С	D	Е	Specimens	No.
1	Appearance, Construction (JIS C 5402 4.1 4.3)	0	0	0	0	0	25 sets	9
2	Low level contact resistance (EIA-364-23)	0	0	0	0	0	25 sets	10
3	Voltage proof (EIA-364-20)					0	5 sets	11
4	Dry heat (Condition a) (EIA-364-09 EIA-364-17, Method A EIA-364-1000.01, Table 8)	0					5 sets	12
5	Mechanical operation, 25 times (EIA-364-09)		0	0			10 sets	13
6	Thermal shock (EIA-364-32 Condition 1)		0				5 sets	14
7	Damp heat, cyclic (EIA-364-31 EIA-364-1000.01, Table 2)		0				5 sets	15
8	Dry heat (Condition b) (EIA-364-17, Method A EIA-364-1000.01, Table 9)			0			5 sets	16

9	Vibration (EIA-364-28 Condition V, Letter D)			0			5 sets	17
10	Flowing mixed gas corrosion (EIA-364-09 EIA-364-17, Method A EIA-364-1000.01, Table 9 EIA-364-65 CLASS IIA)				0		5 sets	19
11	Thermal disturbance (EIA-364-1000.01, Table 4)				0		5 sets	21
12	Mechanical operation, 3 times (EIA-364-09)	0	0		0		15 sets	22
13	Mechanical operation, 100 times (EIA-364-09)					0	5 sets	23

Note) In [Voltage proof] test, as mounting board is different from [Low level contact resistance], different specimens are used.

### Table for each test measurement item

Test item No.	Test item	(1)	(2)	(3)	(4)
4	Dry heat (Condition a)	0	0		
5	Mechanical operation, 25 times	0	0		
6	Thermal shock	0	0		
7	Damp heat, cyclic	0	0		
8	Dry heat (Condition b)	0	0		
9	Vibration	0	0		0
10	Flowing mixed gas corrosion	0	0		
11	Thermal disturbance	0	0		
12	Mechanical operation, 3 times	0	0		
13	Mechanical operation, 100 times	0	0	0	

Remarks: (1) Appearance, Construction

- (2) Low level contact resistance
- (3) Voltage proof
- (4) Electrical discontinuity

## [7] Test results

See the page which describes each test item. See the page shown below for variation graph and result data.

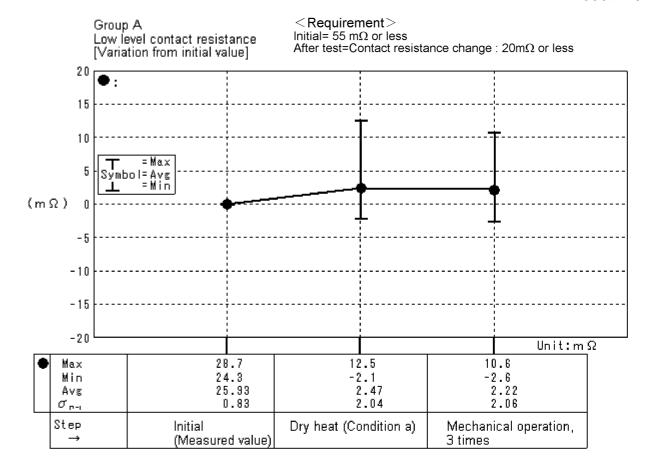
Low Level Contact Resistance, graphs and result data.

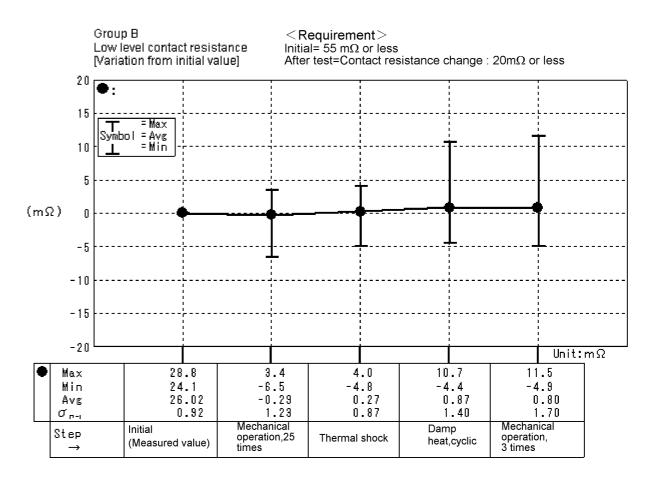
See page 5 for Groups A and B.

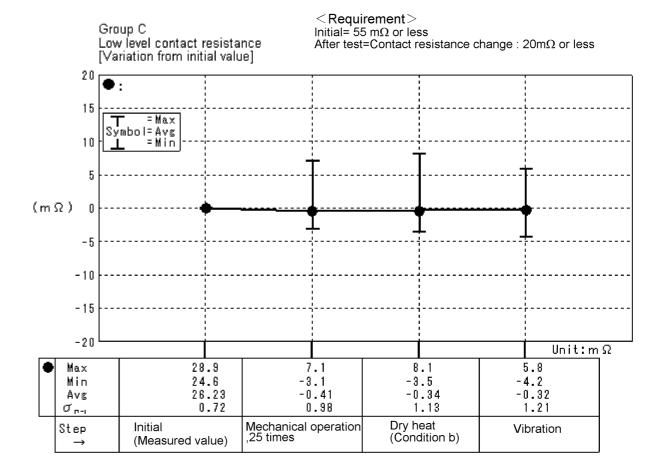
See page 6 for Group C.

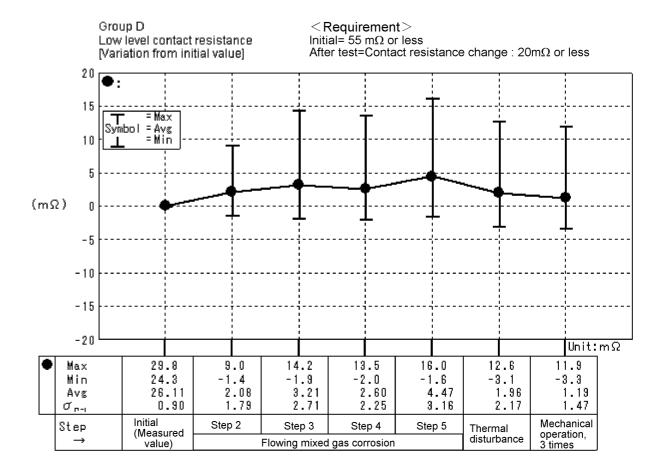
See page 7 for Group D.

See page 8 for Group E.



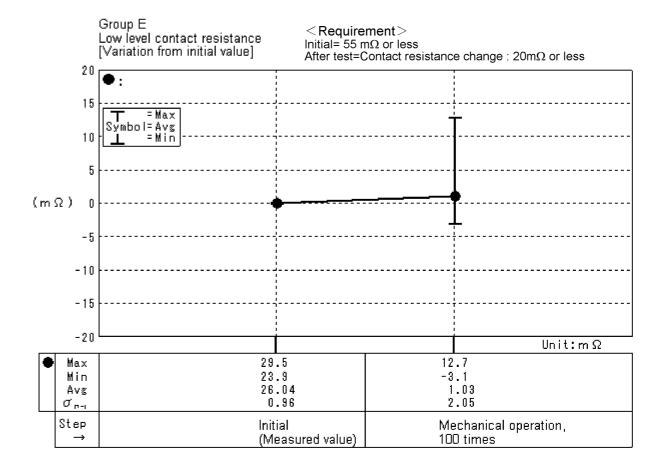






### <Detail of steps, Flowing mixed gas corrosion test>

Steps	
1	Mechanical operation, 25 times
2	Dry heat (after rest in mated)
3	Flowing mixed gas corrosion (after rest for 7 days in unmated)
4	Mechanical operation, 1 time
5	Flowing mixed gas corrosion (after rest for 7 days in mated)



## 1. Appearance, Construction

1.1 Requirements

Appearance, Construction: No defect such as breakage or crack on the

component.

Intermateability: No defect in mating.

1.2 Test method

Appearance, Construction: Check visually with a magnifying glass for any defect

such as breakage or crack.

Intermateability: Check for any defect when specimens are mated with

the applicable connector.

1.3 Test results

Appearance, Construction: No defect. Intermateability: No defect.

### 2. Low level contact resistance

### 2.1 Requirements

55 m $\Omega$  or less

### 2.2 Test method

The measurements are conducted according to the conditions specified in table below:

Open circuit voltage	20 mV a.c. or less, 1 kHz
Test current	1 mA a.c.

Measuring method:

Measured by milliohm-meter at the points shown in the following figure.

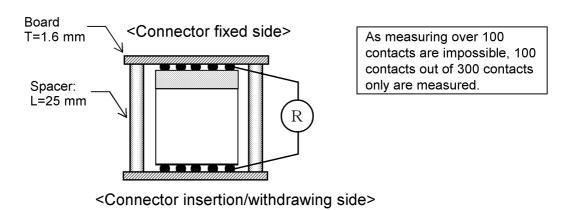


Figure: Measuring points

### 2.3 Test equipment

Test equipment	Model	Manufacturer
Milliohm-meter	4338B	Agilent Technologies

### 2.4 Test results

Groups A to E

Unit:  $m\Omega$ 

Max	29.8
Min	23.9
Avg	26.07
თ <sub>n-1</sub>	0.88

## 3. Voltage proof

### 3.1 Requirements

No defect such as dielectric breakdown or flashover.

### 3.2 Test method

Voltage proof is confirmed according to the conditions specified in table below:

Test voltage	150 V a.c.
Duration	For 60 s

Imposing method: Test voltage is raised in a rate of 500 V/s or less until it

reaches the required value.

Leak current: Judged dielectric breakdown at 2 mA

Measuring point: Between adjacent signal contacts (Between Contact No. C14-

D14 and Between Contact No. C14-C15)

Between signal contacts and ground (Between C14-ground

contact)

Mated/Unmated: Mated

### 3.3 Test equipment

Test equipment	Model	Manufacturer
Voltage proof tester	TOS8750	Kikusui Electronics

### 3.4 Test results

Between adjacent signal contacts No defect.

Between signal contacts and ground No defect.

## 4. Dry heat (Condition a)

### 4.1 Requirements

Appearance, Construction: No defect such as breakage or crack on the

component.

Low level contact resistance: Contact resistance change :  $20m\Omega$  or less.

### 4.2 Test method

After 25 times of Mechanical operations for <insertion/withdrawing side of the connector> are conducted, the tests are conducted according to the conditions specified in table below:

Temperature	105 °C ± 2 °C
Duration	120 h

Mated/Unmated: Mated

Recovery: After the test, let the specimens rest in ambient temperature

for 1 h to 2 h.

### 4.3 Test equipment

Test equipment	Model	Manufacturer
Constant high temperature chamber	STPS-212	Espec

### 4.4 Test results

Appearance, Construction: No defect.

Low level contact resistance: See page 5 for graph and result data.

### 5. Mechanical operation, 25 times

### 5.1 Requirements

Appearance, Construction: No defect such as remarkable abrasion, breakage or

crack on the component.

Low level contact resistance: Contact resistance change :  $20m\Omega$  or less.

### 5.2 Test method

25 times of insertions and withdrawings are conducted at a speed of 300 times/h or less.

Note) Insertions and withdrawings are conducted for <insertion/withdrawing side of the connector> only.

### 5.3 Test results

Appearance, Construction:

Group B: No defect.

Group C: No defect.

Low level contact resistance:

Groups B and C

Variation from initial value

Unit:  $m\Omega$ 

Max	7.1
Min	-6.5
Avg	-0.36
σ <sub>n-1</sub>	1.11

### 6. Thermal shock

### 6.1 Requirements

Appearance, Construction: No defect such as breakage or crack on the

component.

Low level contact resistance: Contact resistance change :  $20m\Omega$  or less.

### 6.2 Test method

The test is conducted according to the conditions specified in table below:

Step	1	2
Temperature (°C)	-55 ± 3	85 ± 2
Duration (min)	30	30

Note) Chamber transfer time is 2 min to 3 min.

Number of cycles: 10 cycles are conducted with the above condition as 1 cycle.

Mated/Unmated: Mated

Recovery: After the test, let the specimens rest in ambient temperature

for 30 min.

### 6.3 Test equipment

Test equipment	Model	Manufacturer
Thermal shock test chamber	TSA-71H	Espec

### 6.4 Test results

Appearance, Construction: No defect.

Low level contact resistance: See page 5 for graph and result data.

### 7. Damp heat, cyclic

### 7.1 Requirements

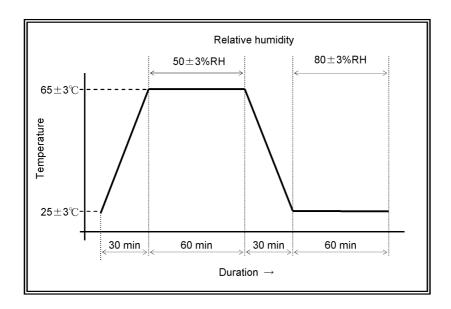
Appearance, Construction: No defect such as breakage, crack or corrosion

which impairs the function of the component.

Low level contact resistance: Contact resistance change :  $20m\Omega$  or less.

#### 7.2 Test method

After let the specimens rest in standard pre-drying condition (50 °C) for 24 h, the test is conducted according to the conditions shown in drawing below:



Number of cycles: 24 cycles are conducted with the above condition as 1 cycle.

Mated/Unmated: Mated

Recovery: After the test, let the specimens rest in ambient temperature

for 5 h.

### 7.3 Test equipment

Test equipment	Model	Manufacturer
Constant temperature chamber	ST-120B1	Espec
Constant temperature and humidity chamber	PSL-4KPH	Espec

### 7.4 Test results

Appearance, Construction: No defect.

Low level contact resistance: See page 5 for graph and result data.

## 8. Dry heat (Condition b)

8.1 Requirements

Appearance, Construction: No defect such as breakage or crack on the

component.

Low level contact resistance: Contact resistance change :  $20m\Omega$  or less.

8.2 Test method

The test is conducted according to the conditions specified in table below:

Temperature	115 °C ± 2 °C
Duration	24 h

Mated/Unmated: Mated

Recovery: After the test, let the specimens rest in ambient temperature

for 1 h to 2 h.

### 8.3 Test equipment

Test equipment	Model	Manufacturer
Constant low temperature chamber	MC-810	Espec

### 8.4 Test results

Appearance, Construction: No defect.

Low level contact resistance: See page 6 for graph and result data.

### 9. Vibration

### 9.1 Requirements

Appearance, Construction: No defect such as breakage or crack on the

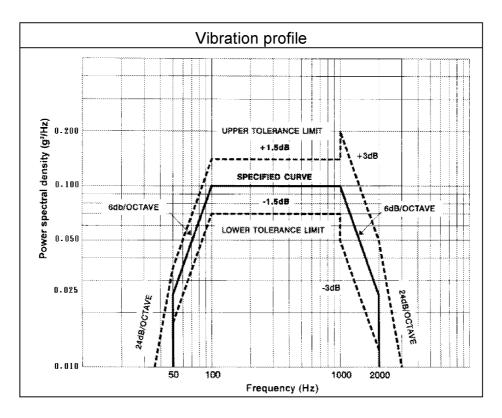
component.

Low level contact resistance: Contact resistance change :  $20m\Omega$  or less. Electrical discontinuity: No electrical discontinuity of 1  $\mu s$  or more.

#### 9.2 Test method

The test is conducted according to the conditions specified in table below:

Frequency range	100 Hz to 1000 Hz	
Acceleration, spectrum density	9.617 (m/s <sup>2</sup> ) <sup>2</sup> /Hz [0.1 g <sup>2</sup> /Hz]	
Initial inclination	6 dB/oct (50 Hz to 100 Hz)	
Final inclination	-6 dB/oct (1000 Hz to 2000 Hz)	
Duration	3 axial directions, 90 min each, 270 min in total	



Test voltage: 5 V d.c.
Test current: 100 mA d.c.

Note 1: [Electrical discontinuity] is checked continuously only on Contact No. 1 of each specimen during the test.

Note 2: Exclusive-use spacer is installed between boards and tests are conducted in the condition that P-side and S-side are completely fixed

## 9.3 Test equipment

Test equipment	Model	Manufacturer
Vibration testing machine	F-300BM/A-E78	Emic
Digital oscilloscope	9360	Lecroy
Variable constant dc volt and ampere generator	PAC35-3	Kikusui Electronics

### 9.4 Test results

Appearance, Construction: No defect.

Low level contact resistance: See page 6 for graph and result data.

Electrical discontinuity: No electrical discontinuity of 1  $\mu s$  or more.

## 10. Flowing mixed gas corrosion

### 10.1 Requirements

Appearance, Construction: No defect such as corrosion which impairs the

function of connector.

Low level contact resistance: Contact resistance change :  $20m\Omega$  or less.

### 10.2 Test method

The tests are conducted according to the steps specified in table below:

Steps↓	
1	Mechanical operation, 25 times
2	Dry heat (after rest in mated)
3	Flowing mixed gas corrosion (after rest for 7 days in unmated)
4	Mechanical operation, 1 time
5	Flowing mixed gas corrosion (after rest for 7 days in mated )

<sup>\*</sup> In Steps 1 and 4, insertions and withdrawings are conducted at a rate of 300 times/h or less in <insertion/withdrawing side of the connector> only.

### <<Dry heat testing condition>>

Temperature	115 °C ± 2 °C
Duration	24 h

Recovery: After the test, let the specimens rest in ambient temperature for 1 h to 2 h.

### <<Mixed gas corrosion testing condition>>

_	_		
Gas concentration	H <sub>2</sub> S	10 ± 5 ppb	
	$NO_2$	200 ± 50 ppb	
Gas concentration	Cl <sub>2</sub>	10 ± 3 ppb	
	SO <sub>2</sub>	100 ± 20 ppb	
Temperature		30 °C ± 1 °C	
Humidity		70 %RH ± 2 %RH	

Recovery: After the test, let the specimens rest in ambient temperature for 2 h or more.

### Intermediate measuring

After Steps 2 to 4, [Low level contact resistance] tests are conducted.

# 10.3 Test equipment

Test equipment	Model	Manufacturer
Constant high temperature chamber	PS-212	Espec
Constant flow type gas corrosion testing machine	GH-180MT	Yamazaki Seiki

### 10.4 Test results

Appearance, Construction: No defect.

Low level contact resistance: See page 7 for graph and result data.

### 11. Thermal disturbance

### 11.1 Requirements

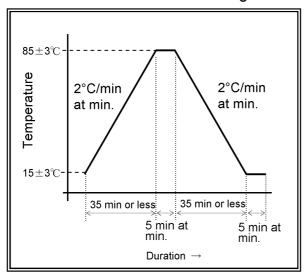
Appearance, Construction: No defect such as breakage, crack or corrosion

which impairs the function of the component.

Low level contact resistance: Contact resistance change :  $20m\Omega$  or less.

### 11.2 Test method

The tests are conducted according to the conditions specified in diagram below:



Number of cycles: 10 cycles are conducted with the above condition as 1 cycle.

Mated/Unmated: Mated

Recovery: After the test, let the specimens rest in ambient temperature for

1 h to 2 h.

### 11.3 Test equipment

Test equipment	Model	Manufacturer
Constant temperature and humidity chamber	PSL-4KPH	Espec

### 11.4 Test results

Appearance, Construction: No defect.

Low level contact resistance: See page 7 for graph and result data.

### 12. Mechanical operation, 3 times

### 12.1 Requirements

Appearance, Construction: No defect such as remarkable abrasion, breakage or

crack on the component.

Low level contact resistance: Contact resistance change :  $20m\Omega$  or less.

### 12.2 Test method

3 times of insertions and withdrawings are conducted at a speed of 300 times/h or less.

Note) Insertions and withdrawings are conducted for <insertion/withdrawing side of the connector> only.

### 12.3 Test results

Appearance, Construction:

Group A: No defect.
Group B: No defect.
Group D: No defect.

Low level contact resistance: See page 7 for graph and result data.

### 13. Mechanical operation, 100 times

13.1 Requirements

Appearance, Construction: No defect such as remarkable abrasion, breakage or

crack on the component.

Low level contact resistance: Contact resistance change :  $20m\Omega$  or less.

Voltage proof: No defect such as dielectric breakdown or flashover.

13.2 Test method

100 times of insertions and withdrawings are conducted at a speed of 300 times/h

or less.

Note) Insertions and withdrawings are conducted for <insertion/withdrawing side

of the connector> only.

13.3 Test results

Appearance, Construction: No defect.

Low level contact resistance: See page 8 for graph and result data.

Voltage proof:

Between adjacent signal contacts No defect.

Between signal contacts and ground No defect.